



Latest Research on Electronic Noise

Guest Editor:

Dr. Graziella Scandurra
Department of Engineering,
University of Messina, 98166
Messina, Italy

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Message from the Guest Editor

Electronic noise has often been considered a problem, and is seen as a disturbance to be eliminated or, at least, reduced as much as possible. However, having its origins in the interaction between matter and charged particles and carrying information about the phenomena that occur at the microscopic level, it can give useful information on the structure of the device under test (DUT) or on its working mechanisms. In this sense, therefore, measuring noise is a powerful device and material characterization technique. This Special Issue aims to collect works that address noise from different points of view: as a knowledge tool or as an issue to be controlled and reduced. Physical interpretations, models, applications, dedicated instrumentation, and measurements are among the topics that we intend to explore.





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Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

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MDPI, St. Alban-Anlage 66
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